

Notice of References Cited	Application/Control No. 10/583,505		Applicant(s)/Patent Under Reexamination MEYER, JASON	
	Examiner ALLEN CHAN		Art Unit 3714	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0058727 A1	03-2004	Marks et al.	463/020
*	B	US-2003/0190943 A1	10-2003	Walker et al.	463/17
*	C	US-2003/0190942 A1	10-2003	Kaminkow et al.	463/16
*	D	US-2003/0069066 A1	04-2003	Seelig et al.	463/20
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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